Exhibit

PB 02 0018

INVENTION QUESTIONNAIRE

Date: $\frac{(4/03/63)}{}$
Name: MARK C. INLOW
Telephone number: <u>2-8618</u> Fax number: <u>378-7753</u>
E-mail address: Mank in low @ Tellus, Comail stop: 143
Specific product where your invention will or most likely be implemented (e.g. TITAN
NOT ALL TEST ENGINEERING FUNCTIONAL TOST INTERFACES EST
Feature package and release date, if applicable, (e.g. FP1.0 - to be released 1/31/02; no feature package determined yet, etc.):
Other products or applications where your invention may be implemented: AU FRODICTION SWITCH & PORT OF MPLEK SUFLIVES / BACKPWINES
Your Sales/Geographic region (e.g., North America): WORTH AWGEOGRAPH
What is the title of your invention? ELECTROHIC INSERTION FATRACTION CYCLE COUNTER AND LOSGER DEVICE,
What is your invention in "simple terms"? (e.g. what is being patented—a method/process/algorithm for synchronizing network elements, an apparatus for synchronizing network elements)
EXTRACTION CYCLES OF BACK PLANT CONNECTORIZATION IN THE MUNICIPAL AND PORT SHE
To what technology does your invention generally relate? SACK PLANE CONNECTOR RATION OF SUITCH OF PORT TELCOM SHENES 30H ELECTRICAL AND OPTICAL
Describe the problem your invention is trying to solve: HIGH DENSITY BACKPLANE KONNECTORS MATING CYCLES CAUSE WEAR WITHE FORM OF MECHANICAL & INTING OF THE CONNECTOR CONTACTS THIS WEAR CAN CAUGE INTERM WITHOUT FAILURES CAUSED BY
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INSERT/EXTRACT CYCLES THROUGHOUT THE BACKPLANE LIFE CYCLE. THIS APPROACH WOULD BE NEW IN THE CASE OF BOTH ELECTRICAL AND OPTION CONNECTORIZATION MONITORING. Describe in detail how your invention works: THE CONNECTOR USAGE COUNTER IS CONTAINED ON A SMALL PCB (RINTED CLROVIT BANE) OR INCORPORATED ON THE BACKLANE ASSEMBLY A SMALL EMBEDED MICROCONTECLES.
Describe in detail how your invention works: THE CONNECTOR IS CONTRIBLE ON A SMALL PCB (RINTED CLROVIT BOME) OR INCORPORATED ON THE SKEPLANE ASSEMBLY A SMALL EMBEDED MICRO-CONTROLLER
Describe in detail how your invention works: THE CONNECTOR IS CONTRIVED ON A SMALL PCB (RINTED CLROVIT BOME) OR INCORPORATED ON THE BACKHANE ASSEMBLY A SMALL EMBEDED MICRO-CONTROLLER
Describe in detail how your invention works: HE CONNECTOR IS CONTRINED ON A SMALL PCB (RINTED CIRCUIT BONE) OR INCORPORATED ON THE BACKHAME ASSETTIBLY A SMALL EMBEDED MICROCONTROLLER
Describe in detail how your invention works: HE CONNECTE USAGE CONNECT IS CONTAINED ON A SMALL PCB (RINTED CIRCUIT BONE) IN INCORPORATED ON THE BAKKLINE ASSEMBLY A SMALL EMBEDED MICRO-CONTROLLER
HE CONNECTOR USAGE COUNTER IS CONTINUED ON A SMALL PCB (PRINTED CIRCUIT BONE) A INCORPORATED ON THE BACKPLANE ASSEMBLY A SMALL EMBEDED MICRO-CONTROLLER
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How easily could Tellabs independently detect another's use of your invention?
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List by name all persons who may have contributed to your invention. (If any such person is not a Tellahs employee, indicate their relationship to Tellahs.) SEE HOTE MANAGER MARY LOWAS - SALES REP TERROWE C
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Ma Chu di/48/22 Signature Dated
Name: First: MARK Middle: CHARLES Last: INLOW
Home Address: 46\$1 DEJON AVENUE
City: 4545 State: 11 Zip: 69532-1535
County: DJ PASE Country: USA
Telephone: (home) (636) 968-9624 (business) (631) 376-8618
Citizenship: US

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Functional Hardware Description Document

and Firmware Programming Instructions

for

Connector Counter 80:6511

Approvals							
· Title	Signature	Date	Title	Signature	Date.		
Author Mark Inlow		-					
Manager Jeff Hotz							

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4. Calibration and Preventive Maintenance

There is no calibration required for the Connector Counter PCB. Preventive maintenance is not required for the Connector Counter PCB.

5. High-Level Connector Counter Hardware Description

The CC uses a PIC micro controller port to interface with the UUT via a 28 pin header located on the rear of each test interface. Pin 5 brings the count signal from the UUT. Future designs also may incorporate this counter design on the test interface-itself, eliminating the need for a separate daughter card. The CC is composed of a custom Test Engineering-PCB that connects to the test interface backplane via a 28 pin header. The functional test interface provides the necessary power and signals to communicate and control the CC. The following is a listing and description of the CC's hardware blocks and electrical interconnects. Refer to Figure 1 for a block diagram of the interface. The sections below describe each block.

5.1 Count Input Conditioning

The UUT provides a ground (low) when the UUT is inserted into the test interface. The test interface designer should use either the MODULE PRESENT signal available on most new product module designs. If this signal is not available, simply pick one digital ground pin on the UUT connector, isolate this from ground on the test interface, and route this signal to the CC's 28 pin header pin 5. This signal is routed through the 28 pin header from the test interface backplane to a 49.9 ohm series current limit resistor. This line is pulled high with a 10K ohm pull-up resistor. CRI clamps unwanted transients. C2 filters out spikes which could cause false counts. The count input signal is routed to the uC port RB4 configured as an input.

5.2 Address Switches

There is a four position DIP switch with one side of each switch tied to +5 VDC and the other side of each switch has an associated pull-down resistor which is also connected to the uC ports RAO through RA3. The switches set the HEX address of the CC which is read by the uC at power on reset. Any unique address may be chosen in the range of 00H to 0xEFH. There is no default.

5.3 Power Fail Detect Circuit

The +5 VDC supply voltage derived from the test interface backplane is monitored by a Dallas Semiconductor DS1811R-10 5V EconoReset IC with an open drain output which is pulled high via a 10K ohm pull-up resistor. The DS1811R's output which is connected to port RB0_INT of the uC is set to transition low when +5 VDC falls below 4.35V (typical). This high to low transition causes a hardware interrupt to the uC which its firmware then saves the current insertion count from RAM to non-volatile EEPROM.

5.4 Microprocessor and Clock Oscillator

The microprocessor implemented in the CC design is a Microcip Technology Flash based micro controller with 1024 words of program memory, 68 bytes of data RAM, 64 bytes of EEPROM and 13 I/O port pins capable of sinking or sourcing 25 MA of current each. There is also an internal power-up reset circuit, two general purpose programmable timers and four interrupt sources. The uC can operate down to a supply voltage of 2.0 VDC. The uC clock is derived from a parallel cut 11.059 MHZ crystal connected to the uC's OSC1 input and OSC2 output respectfully. Two external capacitors are connected on each side of the crystal to provide increased stability of the oscillator. The values were chosen based on the manufacturers recommendations: The 11.059 MHZ clock is internally divided by four to provide a 36.2 nanosecond instruction cycle.

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5.5 R\$232 / R\$485 I/O Port Drivers

Serial communications to and from the CC are provided by the uC ports and level converted to the RS232 standard utilizing a Maxim Semiconductor MAX232A IC. The IC provides the +/-9 VDC required from an internal charge pump circuit and four external electrolytic filter capacitors. The TX and RX signals are routed to the 28 pin header to allow connectivity to the test interface backplane directly or are available at an on board RJ11 jack. If multiple CC's are required to keep track of the connector count on multiple test interfaces, a Linear Technology RS485 transceiver LTC485 is also connected to the uC serial port lines and is available at both the 28 pin header and the RJ11 jack. Depending on the address switches set on each CC, response occurs only on the RS485 bus when the CC sees its unique address.

5.6 LED Status Indicators and ISP Port

There are three LED status indicators provided on the CC. These are sourced from three uC ports. These lines are also routed to the 28 pin header If the test interface should require to read the status directly.

- 1) The "AWAKE" LED illuminates green when the uC comes out of "sleep" mode.
- 2) The "ADDR DETECT" LED illuminates red when the CC is communicated with and its own address matches.
- 3) The "TEST LED" is a spare LED available for debug and future designs.

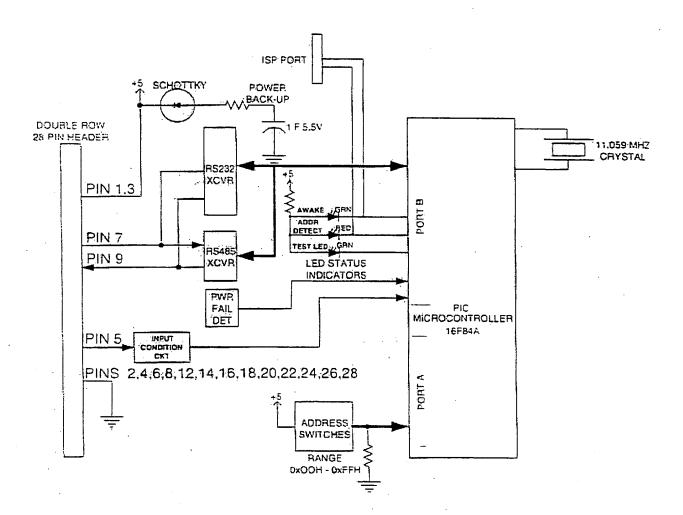
The firmware program for the CC contained in FLASH within the uC may be programmed through the ISP port connector P2. This connector provides the necessary programming signals to the uC pins from a Microchip PIC device programmer of OEM equivalent.

5.7 1 Farad Backup Capacitor

The test interface is powered down and $\pm 5^\circ$ VDC is not available until just before the functional test starts. If the operator plugs the UUT into the interface before power is applied an insertion count would be missed. To correct for this problem a large value low leakage capacitor is used to keep power available to the CC from the last test. A 1 Farad 5.5vdc rated capacitor and 82 ohm series charge resistor provide 5 VDC to the uC. This capacitor charges to approximately VCC (± 5 MDC) through the 82 ohm current limit resistor. This limits the inrush current of the capacitor as power is applied. This voltage supplies the uC only through a steering schonky diode. This limits the current draw on the capacitor to the uC only for optimum charge time between tests.

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Figure 1. 80:6511 Connector Counter Block Diagram



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6. Reference Section

6.0.1. uC Port I/O Bit Definition

Table 8: uC Pin Definition

1/0	Function
RA0	ICC address select input ADDR0
RA1	CC address select input ADDR1
RA2	CC address select input ADDR2
RA3	CC address select input ADDR3
RA4_TOCKI	Unused input (pulled high)
RB0_INT	Power Fail Detect interrupt input
RB1	"AWAKE" LED indicator output
RB2	Serial TXID output
RB3	Serial RXD input
RB4	Connector insert/extract input
RB5	RXD Start Bit interrupt Detect input
RB6	"TEST" LED indicator output
RB7	"ADDR: DETECT" LED output
MCLR	Power-on clear input (pulled high)

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6.1 Firmware Description

The firmware of approximately 400 words long is stored in the 1024 word flash memory within the uC. The firmware is programmed into the uC via an ISP programming cable and a Microchip Piestart Plus development programmer or equivalent. Briefly, the firmware program performs the following functions. At power-up reset all the I/O ports are initialized as well as the uC internal registers. The interrupts are enabled and the address switches are read. The insertion count value that was in the EEPROM is also read and is used to update the RAM count location. The program then goes into a "sleep" mode which powers down the uC clock oscillator but leaves the current I/O port values as they are. This limits the uC current draw down to a few microamps and also keeps any unwanted uC 11.059 MHZ clock noise from affecting the UUT during the functional test.

The uC "awakes" from sleep mode upon receipt of a start character (high to low transition on port RB5). The program then loops until a full serial character is received. The CC looks for and acts on the following serial commands from the funtional test CVI calling program. Each command shall be proceeded by the HEX address of the CC being talked to and terminated by a carriage return character (HEX 0x0d).

xx = hex address of CC being address in the range of 00 to ff HEX.

CR = carriage return character (HEX 0x0D)

- 1) xxclear(CR) Clears the CC's current inscriion/extraction count to zero.
- 2) xxread(CR) Reads the CC's current insertion/extraction count.

The program also responds to interrupts from the following sources and the o'C "tawakes" from each.

- 1) An insertion/extraction detected. The insertion/extraction count is incriminated by 1.
- 2) When +5 VDC falls below 4,35 (typical). The current inscrition/extraction count is saved in EEPROM.
- 3) Time-out of the uC timer (time) used to produce debounce delay of the insertion/extraction input.

The uC also enables a watchdog timer with a time-out value of 2.3 seconds. The main loop of the program clears the watchdog timer count value before it times out during normal program operation. If a serial communication failure or other program corruption from a power glitch occurs the watchdog times out and causes a hardware reset. This keeps the CC from ever "hanging up" and not responding.

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7. Configuration Management of Microchip Files

Microchip files are under configuration management and are located on tlabbd-8 in the digdoc/docs/microchip directory. General Microchip Files (used by Test Engineering for Development) are stored here as zipped files. The filename of the zipped file is the revision level: Hardware documents will refer to this revision filename as the current configuration data required for the Microchip device.

To retrieve a specific revision level of Microchip configuration files, use either a NFS connection or FTP élient to map to tiabbd-8 digdoc/docs/microchip directory. Select the desired Microchip zip file (i.e. con_ctr1.ZIP) and copy to the workstation where Microchip Mplab software is running.

There are two options to UNZIP the Microchip files:

Option 1:

Copy the zipped file to your UNIX directory and use the UNZIP command. This will create the Microchip file directory in your UNIX account containing the unzipped files.

Path to ZIP/UNZIP Utilities is /usr/local/gnu/bin

Example: sunk44> unzip con_ctrl.zip

This will explode the Microchip files in a directory called con_ctr1/. Then use NFS or FTP client to copy over to the PC workstation. It would be wise to create a separate directory containing these files. Remember the location of the files when using the Mplab software.

To view the contents of a zipped file in UNIX type the following: sunk44> unzip -1 con_cut1 zip (The -1 will list the contents of the file)

Option 2:

Copy the zipped file directly to the PC workstation using NFS or FTP client and use the PKUNZIP utility. Be sure that the PKUNZIP.exc is available on the workstation.

After the zipped file has been copied to the workstation, open a M5-DOS prompt window. Now change to the appropriate directory where the zipped file exists.

cd\uscrs\john_doc (directory where con_ctrl.zip exists)

Example: c:\users\john_doc> pkunzip con_ctrl.zip

This will explode the Microchip files in a directory called chasers/john_doe\con_ctrl. Remember the location of the files when using the Microchip Mplab software.

For additional information on Test Software Release and Revision Control see 05.0012.0000

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7.1 Firmware Programming Instructions

The following set of instructions are provided to assist Test Engineering or Eab Services in programming the required firmware into the CC.

The following items are required for programming:

- 1) Microchip Corporation Piestart Plus REV, V1.50 or greater and PC based software
- 2) PC running windows NT or Windows 98/2000 with Microchip Mplab software development tool installed. (This is available from Microchip Web site at ne cost).
- 3) Tellabs built ISP adapter cable (Figure 2)
- 4) Insertion counter module 80.6511 to be programmed

To: Download Firmware:

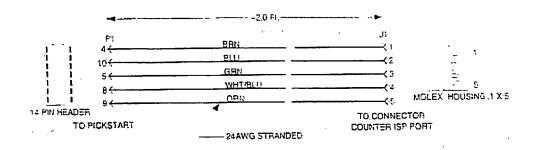
- 1) Install Mplab if necessary on PC. Invoke Mplab.
- Go to PICSTART Plus pull down menu. Choose Enable Programmer Three windows appear.

PICKSTART Plus Programmer Window Program Memory Window Configuration Bits Window

- 3) Under Debug pull-down menu, choose Clear Program Memory,
- 4) Click yes to "Do you want to fill all program memory with 0x3FFF?"
- 5) Under the File pull-down menu, choose Import-Import to Memory
- 6) Find the hex file named con_cntribex located in the directory created containing the un-zipped files described in the above Configuration Management section. Click OK
- 7) After the file is loaded the Program Memory Window will change to show the HEX program code.
- 8) Insure that the current checksum specified in the assembly drawing is displayed, and that the device type selected is PIC16F84A
- 9) Connect the CC to the PICSTART with the adapter cable, observing proper pin polarity at both the ISP port side and the PICSTART side.
- 10) At the PICSTART Plus Programming. Window choose the Program button. Wait for the part to finish being programmed. Note the checksum and insure that it agrees with the current checksum.
- 11) Blank PIC16F84A IC's (PN TE.270041) may also be pre-programmed prior to being placed on the PCB assembly by eliminating the adapter cable and placing the blank part directly into the PIC programmer
- 12) This completes the CC Flash programming. Remove adapter cable from CC:

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Figure 2. ISP Adapter Cable Definition



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